



SLOVENSKI STANDARD SIST EN IEC 62435-4:2018

01-oktober-2018

Elektronske komponente - Dolgoročno skladiščenje elektronskih polprevodniških elementov - 4. del: Skladiščenje (IEC 62435-4:2018)

Electronic components - Long-term storage of electronic semiconductor devices - Part 4: Storage (IEC 62435-4:2018)

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Ta slovenski standard je istoveten z: **EN IEC 62435-4:2018**
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ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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EUROPEAN STANDARD

EN IEC 62435-4

NORME EUROPÉENNE

EUROPÄISCHE NORM

August 2018

ICS 31.020

English Version

**Electronic components - Long-term storage of electronic
semiconductor devices - Part 4: Storage
(IEC 62435-4:2018)**

Composants électroniques - Stockage de longue durée des
dispositifs électroniques à semiconducteurs - Part 4:
Stockage
(IEC 62435-4:2018)

Elektronische Bauteile - Langzeitlagerung elektronischer
Halbleiterbauelemente - Teil 4: Lagerung
(IEC 62435-4:2018)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 62435-4:2018 (E)**European foreword**

The text of document 47/2469/FDIS, future edition 1 of IEC 62435-4, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62435-4:2018.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2019-04-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2021-07-10

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

https://standards.iteh.ai/catalog/standards/sist/ed80a8bf-b14b-4c9b-883e-37b1b6949ff1/sist-en-iec-62435-4-2018	
IEC 60068-2-17	NOTE Harmonized as EN 60068-2-17
IEC 60721-3-1	NOTE Harmonized as EN IEC 60721-3-1
IEC 60749-30	NOTE Harmonized as EN 60749-30
IEC 61340-5-1	NOTE Harmonized as EN 61340-5-1
IEC 61340-5-3	NOTE Harmonized as EN 61340-5-3
IEC 61760-2	NOTE Harmonized as EN 61760-2
IEC 62258 series	NOTE Harmonized as EN 62258 series
IEC 62435 series	NOTE Harmonized as EN 62435 series
IEC 62435-2	NOTE Harmonized as EN 62435-2

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-20-1	-	Semiconductor devices - Mechanical and climatic test methods - Part 20-1: Handling, packing, labelling and shipping of surface-mount devices sensitive to the combined effect of moisture and soldering heat	EN 60749-20-1	-
IEC/TR 61340-5-2	-	Electrostatics -- Part 5-2: Protection of electronic devices from electrostatic phenomena - User guide	CLC/TR 61340-5-2	-
IEC/TR 62258-3	-	Semiconductor die products -- Part 3:- Recommendations for good practice in handling, packing and storage	EN 62258-3	-
JEDEC J-STD-033	-	Standard for handling, packing, shipping, and use of moisture/reflow sensitive surface mount devices	EN 62435-4	-
MIL-PRF-27401	-	Propellant pressurizing agent nitrogen		
MIL-PRF-81705	-	ESD Materials, Bags and Performance Specification		

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INTERNATIONAL STANDARD

**Electronic components – Long-term storage of electronic semiconductor devices –
Part 4: Storage**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTRONIC COMPONENTS – LONG-TERM STORAGE
OF ELECTRONIC SEMICONDUCTOR DEVICES –**
Part 4: Storage
FOREWORD

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International Standard IEC 62435-4 has been prepared by IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47/2469/FDIS	47/2486/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62435 series, published under the general title *Electronic components – Long-term storage of electronic semiconductor devices*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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